

Notice of References Cited	Application/Control No. 10/777,659		Applicant(s)/Patent Under Reexamination NAKANISHI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,322,914	11-2001	Chow et al.	429/13
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	J	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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